

<b>Notice of References Cited</b>	Application/Control No. 10/810,641	Applicant(s)/Patent Under Reexamination FURUKAWA ET AL.	
	Examiner Daniel F. Hajnik	Art Unit 2671	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,320,578	11-2001	Shiitani et al.	345/419
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Malik et al., "Recovering Photometric Properties Of Architectural Scenes From Photographs", ACM Ditigal Library, Pub 1998, pgs. 207-217
	V	Marchant et al., "Shadow-invariant classification for scenes illuminated by daylight", Journal of the Optical Society of America Vol. 17, No. 11/Nov 2000, pgs. 1952-1961
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.